nexperia

Quarterly Reliability Monitoring Results

Quarters: Q1/2022 to Q4/2023

Based on structural similarity

Supplier		User Part Number						
Nexperia B.V. Name of Laboratory Assembly reliability labs		PESD7V1R1BCSF Part Description						
								NXP ICN8 Protection INDI
		BD package						
		Test		Test Conditions	Duration	# Lots	# Quantity	# Rejects
	TEST							
	Pre- and Post-Stress							
# 1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below		
		MIL-STD-750-1						
	HTRB	M1038 Method A						
	High Temperature Reverse	Tj = Tjmax, Vr = 100% of max. datasheet						
# 5	Bias	reverse voltage	1000 hours	92	4040	0		
	тс	JESD22-A104						
# 7	Temperature Cycling	-40 °C to 125°C	1000 cycles	157	6880	0		
	UHAST	JESD22-A118						
# 8 or # 8a	Unbiased HAST	Tamb = 130 °C, RH = 85 %	96 hours	n.a.	n.a.	n.a.		
		JESD22-A102	50 110015	11.a.	11.d.	11.d.		
	AC	Tamb = 121 °C, RH = 100 %						
	Autoclave	Pressure = 205 kPa (29.7 psia)						
	HAST	JESD22-A110						
	Highly Accelerated Stress	Tamb = 130 °C, RH = 85%, VR = 80 % of						
# 9	Test	rated reverse voltage ^[1]	1000 hours	156	6840	0		
		MIL-STD-750 Method 1037						
	IOL	ton = toff, devices powered to insure ΔTj =						
# 10	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	n.a.	n.a.	n.a.		
	RSH	JESD22-A111						
# 20	Resistance to Solder Heat	260 °C ± 5 °C	10 s	n.a.	n.a.	n.a.		
	SD	1 075 000						
# 21	Solderability	J-STD-002		8	240	0		

[1] The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

Calculation of FIT and MTTF

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test # 5) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

NXP ICN8 Protection INDI 4040 0 1 1 951E+00	Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
······································	NXP ICN8	Protection INDI	4040	0	1,1	9,51E+08

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